FAIRCHILD SEMICONDUCTOR™

October 1987
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CD4019BC
Quad AND-OR Select Gate

General Description

The CD4019BC is a complementary MOS quad AND-OR select gate. Low power and high noise margin over a wide voltage range is possible through implementation of N- and P-channel enhancement mode transistors. These complementary MOS (CMOS) transistors provide the building blocks for the 4 "AND-OR select" gate configurations, each consisting of two 2-input AND gates driving a single 2-input OR gate. Selection is accomplished by control bits K_A and K_B. All inputs are protected against static discharge damage.

Features

- Wide supply voltage range: 3.0V to 15V
- High noise immunity: 0.45 V_{DD} (typ.)
- Low power TTL compatibility: Fan out of 2 driving 74L or 1 driving 74LS

Applications

- AND-OR select gating
- Shift-right/shift-left registers
- True/complement selection
- AND/OR/EXCLUSIVE-OR selection

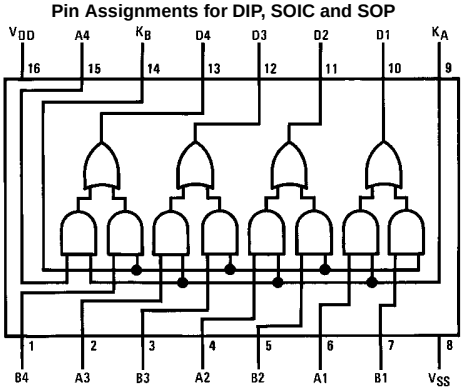
Ordering Code:

Order Number	Package Number	Package Description
CD4019BCM	M16A	16-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow
CD4019BCSJ	M16D	16-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
CD4019BCN	N16E	16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

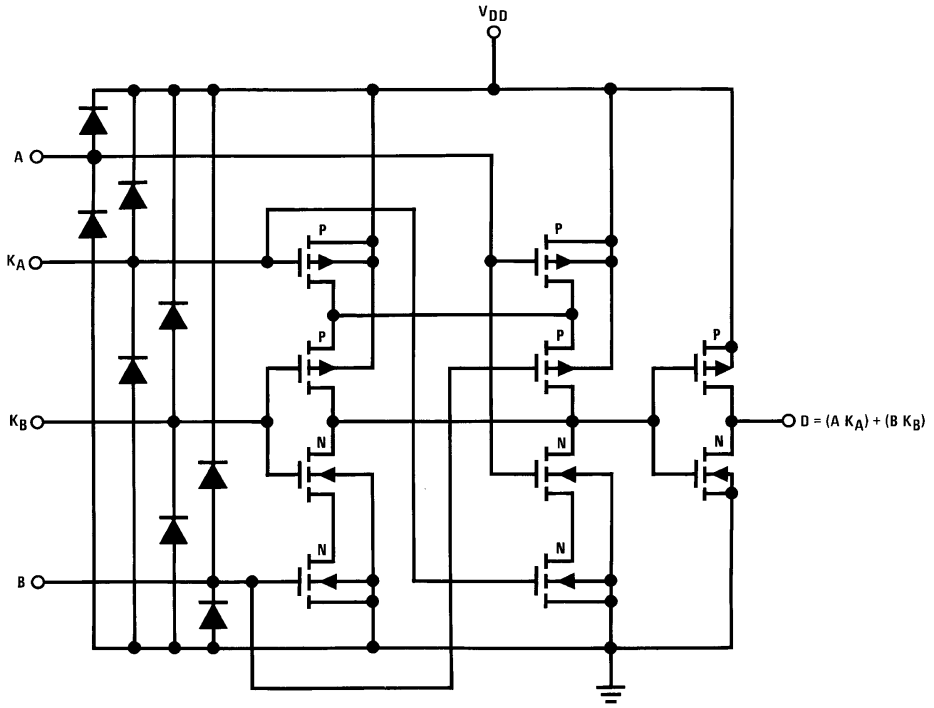
Connection Diagram

Pin Assignments for DIP, SOIC and SOP



Top View

Schematic Diagram



Schematic diagram for 1 of 4 identical stages

Absolute Maximum Ratings(Note 1)

(Note 2)

Supply Voltage (V_{DD})	−0.5V to +18V
Input Voltage (V_{IN})	−0.5V to V_{DD} +0.5V
Storage Temperature Range (T_S)	−65°C to +150°C
Power Dissipation (P_D)	
Dual-In-Line	700 mW
Small Outline	500 mW
Lead Temperature (T_L)	
(Soldering, 10 seconds)	260°C

Recommended Operation Conditions (Note 2)

DC Supply Voltage (V_{DD})	+3V to +15V
Input Voltage (V_{IN})	0V to V_{DD}V
Operating Temperature Range (T_A)	−40°C to +85°C

Note 1: "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed; they are not meant to imply that the devices should be operated at these limits. The tables of "Recommended Operating Conditions" and "Electrical Characteristics" provide conditions for actual device operation.

Note 2: V_{SS} = 0V unless otherwise specified.

DC Electrical Characteristics (Note 3)

Symbol	Parameter	Conditions	−40°C		+25°C			+85°C		Units
			Min	Max	Min	Typ	Max	Min	Max	
I_{DD}	Quiescent Device	V_{DD} = 5V		1		0.03	1		7.5	µA
	Current	V_{DD} = 10V		2		0.05	2		15	µA
		V_{DD} = 15V		4		0.07	4		30	µA
V_{OL}	LOW Level	$\|I_O\|$ < 1 µA								
	Output Voltage	V_{DD} = 5V		0.05		0	0.05		0.05	V
		V_{DD} = 10V		0.05		0	0.05		0.05	V
		V_{DD} = 15V		0.05		0	0.05		0.05	V
V_{OH}	HIGH Level	$\|I_O\|$ < 1 µA								
	Output Voltage	V_{DD} = 5V	4.95		4.95	5		4.95		V
		V_{DD} = 10V	9.95		9.95	10		9.95		V
		V_{DD} = 15V	14.95		14.95	15		14.95		V
V_{IL}	LOW Level	V_{DD} = 5V, V_O = 0.5V or 4.5V		1.5		2	1.5		1.5	V
	Input Voltage	V_{DD} = 10V, V_O = 1.0V or 9.0V		3.0		4	3.0		3.0	V
		V_{DD} = 15V, V_O = 1.5V or 13.5V		4.0		6	4.0		4.0	V
V_{IH}	HIGH Level	V_{DD} = 5V, V_O = 0.5V or 4.5V	3.5		3.5	3		3.5		V
	Input Voltage	V_{DD} = 10V, V_O = 1.0V or 9.0V	7.0		7.0	6		7.0		V
		V_{DD} = 15V, V_O = 1.5V or 13.5V	11.0		11.0	9		11.0		V
I_{OL}	LOW Level Output	V_{DD} = 5V, V_O = 0.4V	0.52		0.44	1		0.36		mA
	Current (Note 4)	V_{DD} = 10V, V_O = 0.5V	1.3		1.1	2.5		0.9		mA
		V_{DD} = 15V, V_O = 1.5V	3.6		3.0	10		2.4		mA
I_{OH}	HIGH Level Output	V_{DD} = 5V, V_O = 4.6V	−0.2		−0.16	−0.4		−0.12		mA
	Current (Note 4)	V_{DD} = 10V, V_O = 9.5V	−0.5		−0.4	−1.0		−0.3		mA
		V_{DD} = 15V, V_O = 13.5V	−1.4		−1.2	−3.0		−1.0		mA
I_{IN}	Input Current	V_{DD} = 15V, V_{IN} = 0V		−0.30		-10^{-5}	−0.30		−1.0	µA
		V_{DD} = 15V, V_{IN} = 15V		0.30		10^{-5}	0.30		1.0	µA

Note 3: V_{SS} = 0V unless otherwise specified.

Note 4: I_{OH} and I_{OL} are tested one output at a time.

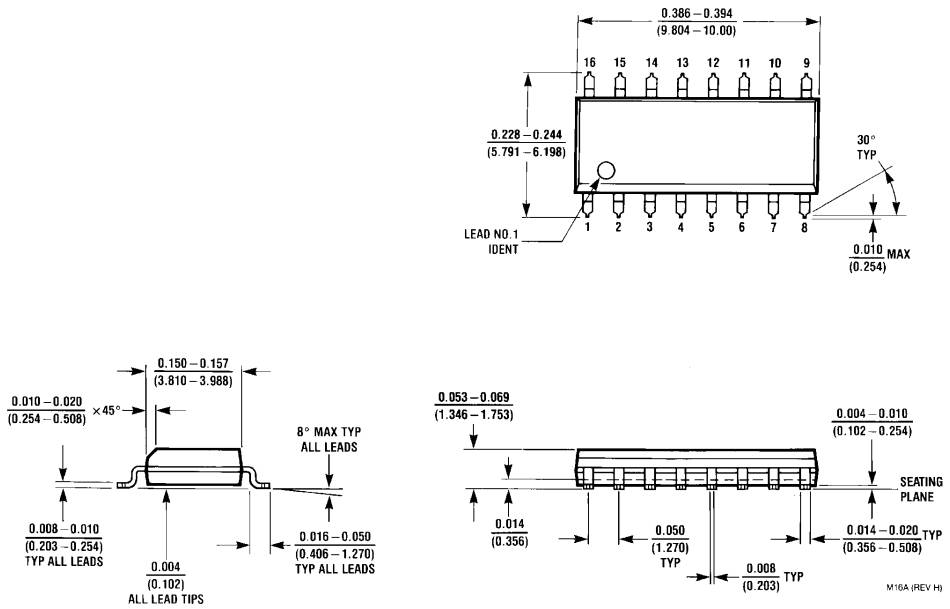
AC Electrical Characteristics (Note 5)

$T_A = 25°C$, $C_L = 50$ pF, $R_L = 200$k, unless otherwise specified

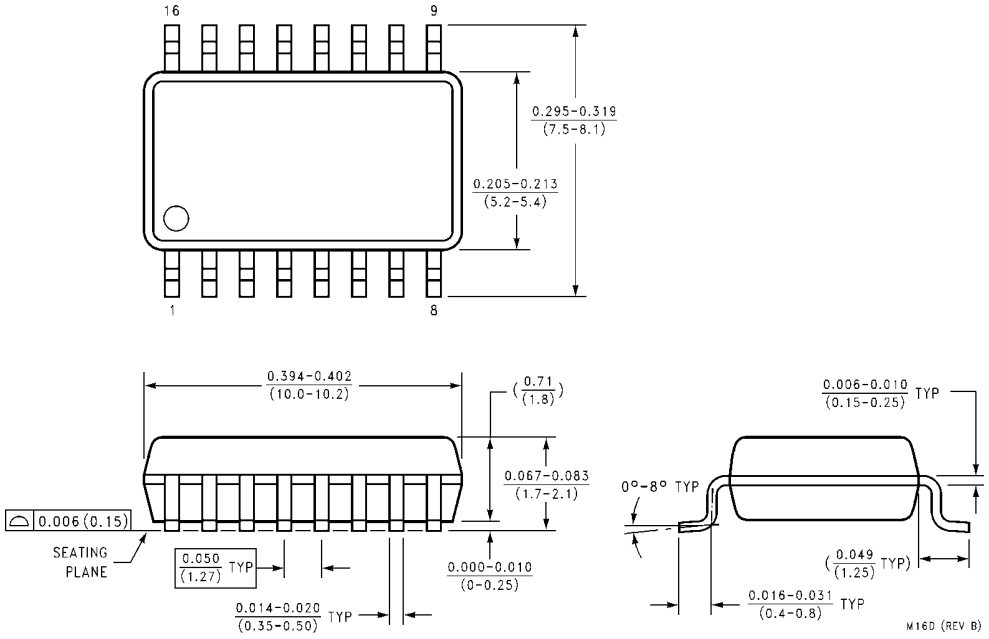
Symbol	Parameter	Conditions	Min	Typ	Max	Units
t_{PHL},	Propagation Delay,	$V_{DD} = 5V$		100	300	ns
t_{PLH}	Input to Output	$V_{DD} = 10V$		50	120	ns
		$V_{DD} = 15V$		45	100	ns
t_{THL}	HIGH-to-LOW Level	$V_{DD} = 5V$		100	200	ns
	Transition Time	$V_{DD} = 10V$		50	100	ns
		$V_{DD} = 15V$		40	80	ns
t_{TLH}	LOW-to-HIGH Level	$V_{DD} = 5V$		150	300	ns
	Transition Time	$V_{DD} = 10V$		70	140	ns
		$V_{DD} = 15V$		50	100	ns
C_{IN}	Input Capacitance	All A and B Inputs		5	7.5	pF
		K_A and K_B Inputs		10	15	pF

Note 5: AC Parameters are guaranteed by DC correlated testing.

Physical Dimensions inches (millimeters) unless otherwise noted

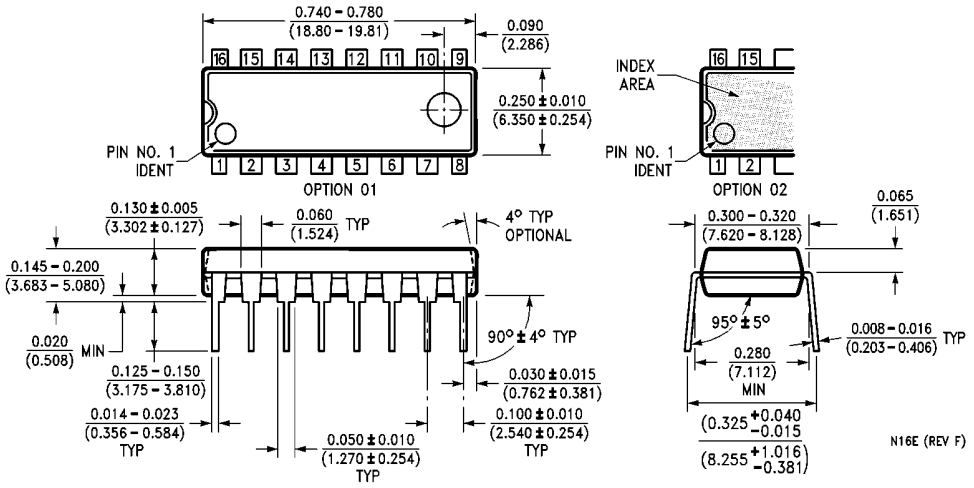


16-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow
Package Number M16A



16-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
Package Number M16D

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide
Package Number N16E

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2. A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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